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APPLICATION NO. FILING DATE		FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.		
10/723,377 11/26/2003		11/26/2003	Tam Minh Tran	TI-36647	8031		
23494	7590	05/02/2006		EXAM	EXAMINER		
TEXAS II P O BOX 6		ENTS INCORPOR	EHNE, CHARLES				
DALLAS,			ART UNIT	PAPER NUMBER			
				2113			
				DATE MAILED: 05/02/2006			

Please find below and/or attached an Office communication concerning this application or proceeding.

			Application No.		Applicant(s)				
		10/723,377		TRAN ET	AL.				
	Office Action Summary	Examiner		Art Unit					
		Charles Ehne		2113					
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply									
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filled after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).									
Status				:					
1) 又	Responsive to communication(s) filed on	26 November 2003	3.						
•	<u> </u>	This action is non-							
·—	,	•		secution	as to the merits is				
٠,۵	3) Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.								
Dienociti	on of Claims	,	.,						
·									
•	Claim(s) <u>11,12,14 and 15</u> is/are pending i	• •		;					
	4a) Of the above claim(s) is/are wit	indrawn from consi	deration.	:					
'	Claim(s) <u>1-10 and 16-18</u> is/are allowed.				:				
·	Claim(s) <u>11,12,14 and 15</u> is/are rejected.				•				
•	Claim(s) is/are objected to.								
8)[Claim(s) are subject to restriction a	and/or election requ	uirement.						
Applicati	on Papers				: :				
9)□	The specification is objected to by the Exa	aminer.							
	10) The drawing(s) filed on is/are: a) accepted or b) objected to by the Examiner.								
<i>,</i> —	Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).								
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).									
11) The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.									
Priority ι	under 35 U.S.C. § 119	•			• :				
•	Acknowledgment is made of a claim for fo ☐ All b)☐ Some * c)☐ None of:	oreign priority under	· 35 U.S.C. § 119(a))-(d) or (f)	•				
۵)ر	1.☐ Certified copies of the priority docu	ments have heen r	eceived		•				
	2. Certified copies of the priority docu			on No	: ,				
	3. Copies of the certified copies of the		• •						
	application from the International B	, ,			· · · · · · · · · · · · · · · · · · ·				
* 5	See the attached detailed Office action for	•	. ,,	ed.	;				
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Attachment(s)									
	ce of References Cited (PTO-892)		Interview Summary						
	ce of Draftsperson's Patent Drawing Review (PTO-94 mation Disclosure Statement(s) (PTO-1449 or PTO/5		Paper No(s)/Mail Da		cation (PTO-152)				
	er No(s)/Mail Date	6)			i				

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DETAILED ACTION

Claim Objections

The numbering of claims is not in accordance with 37 CFR 1.126 which requires the original numbering of the claims to be preserved throughout the prosecution. When claims are canceled, the remaining claims must not be renumbered. When new claims are presented, they must be numbered consecutively beginning with the number next following the highest numbered claims previously presented (whether entered or not).

Misnumbered claims 14-18 are to be renumbered 13-17.

There is insufficient antecedent basis for this limitation in the claim.

Claim Rejections - 35 USC § 112

The following is a quotation of the second paragraph of 35 U.S.C. 112:

The specification shall conclude with one or more claims particularly pointing out and distinctly claiming the subject matter which the applicant regards as his invention.

Claims 14-15 (original) recites the limitation "selected from the group" in line 4.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

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The factual inquiries set forth in *Graham* v. *John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

- 1. Determining the scope and contents of the prior art.
- 2. Ascertaining the differences between the prior art and the claims at issue.
- 3. Resolving the level of ordinary skill in the pertinent art.
- 4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claims 11,12,14 and 15 (original) are rejected under 35 U.S.C. 103(a) as being unpatentable over Hsu (6,457,108) taken in view of Chih (2003/0154437).

As to claim 11, Hsu discloses a memory device with repair capability comprising: a supply voltage (column 4, lines 49-52); power control logic connected to the supply voltage (column 4, lines 46-49); at least one switch connected to the supply voltage (column 4, lines 46-49); a memory array connected to the at least one switch (column 5, lines 44-50); and peripheral logic connected to the at least one switch (column 4, lines 56-57).

Hsu discloses data registers connected to the supply voltage and the at least one switch, wherein the at least one switch is operational to remove power to the peripheral logic, the memory array and selected portions of the data registers in response to power control logic signals such that data is retained in the registers subsequent to power down of the peripheral logic, the memory array, and the selected portions of the repair data registers (column 9, lines 47-50), but fails to disclose that the data is memory repair data.

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Chih does disclose that non-volatile memory can be utilized to store information necessary to repair defective memory arrays (page 1, ¶ 0010, lines 1-5). Chih also discloses that memory repairing data is generally read out of a volatile latch array after the computer system is powered up (page 1, ¶ 0010, lines 5-7).

It would have been obvious to one of ordinary skill in this art at the time of invention by applicant to implement Hsu's method of retaining data during removal of power with Chih's method of retaining memory repair data. A person of ordinary skill in the art would have been motivated to make the modification because Hsu's provides a method to ensure maximum data retention (Hsu: column 1, lines 16-18) which would allow further fault tolerance for consistent data retention when reading memory repair data.

As to claim 12, Chih discloses the memory device according to claim 11, wherein the repair data registers comprise retention latch circuitry operational to store and maintain the memory repair data (page 1, ¶ 0010, lines 5-7).

As to claim 14, Hsu discloses a memory device with repair capability comprising: a supply voltage (column 4, lines 49-52);

power control logic connected to the supply voltage (column 4,lines 46-49);

at least one switch selected from the group consisting of a Vss footer switch, and a Vdd header switch (column 4, lines 54-60);

a memory array connected to the at least one switch (column 5,lines 44-50); and peripheral logic connected to the at least one switch (column 4, lines 56-57).

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Hsu discloses data registers connected to the supply voltage and the at least one switch, wherein the at least one switch is operational to remove power to the peripheral logic, the memory array and selected portions of the data registers in response to power control logic signals such that data is retained in the registers subsequent to power down of the peripheral logic, the memory array, and the selected portions of the repair data registers (column 9, lines 47-50), but fails to disclose that the data is memory repair data.

Chih does disclose that non-volatile memory can be utilized to store information necessary to repair defective memory arrays (page 1, ¶ 0010, lines 1-5). Chih also discloses that memory repairing data is generally read out of a volatile latch array after the computer system is powered up (page 1, ¶ 0010, lines 5-7).

It would have been obvious to one of ordinary skill in this art at the time of invention by applicant to implement Hsu's method of retaining data during removal of power with Chih's method of retaining memory repair data. A person of ordinary skill in the art would have been motivated to make the modification because Hsu's provides a method to ensure maximum data retention (Hsu: column 1, lines 16-18) which would allow further fault tolerance for consistent data retention when reading memory repair data.

As to claim 15, Chih discloses the memory device according to claim 14, wherein the repair data registers comprise retention latch circuitry operational to store and maintain the memory repair data (page 1, ¶ 0010, lines 5-7).

Claims 1-10 and 16-18 (original) are allowed.

The following is an examiner's statement of reasons for allowance:

Claim 1 discloses maintaining power to the power control logic and repair data registers during loss of power to the E-fuse farm and associated memory module circuitry, such that the memory repair information is retained by the memory module during the loss of power to the E-fuse farm and associated memory module circuitry.

Claim 6 discloses maintaining power to the memory module power control logic and memory module repair data registers during loss of power to the E-fuse farm and associated memory module circuitry, such that the memory repair information is retained by the memory module during the loss of power to the E-fuse farm and associated memory module circuitry.

Claim 16 discloses at least one memory module comprising repair data registers, wherein the at least one memory module operates to maintain memory repair data in the repair data registers in response to power management control logic signals during loss of power to portions of the device.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

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Any inquiry concerning this communication or earlier communications from the examiner should be directed to Charles Ehne whose telephone number is (571)-272-2471. The examiner can normally be reached on Monday-Friday 8:30-5:00.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Robert Beausoliel can be reached on (571)-272-3645. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

ROBERT BEAUSOLIEL
SUPERVISORY PATENT EXAMINER